**TOSHIBA** 2SK2855

TOSHIBA FIELD EFFECT TRANSISTOR SILICON N CHANNEL MOS TYPE

## 2 S K 2 8 5 5

**UHF BAND AMPLIFIER APPLICATION** 

### MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Drain-Source Voltage	$ m V_{DSS}$	10	V
Gate-Source Voltage	$v_{GSS}$	±6	V
Drain Current	$I_{\mathbf{D}}$	1.0	A
Drain Power Dissipation	$P_{\mathbf{D}}$	0.5	W
Channel Temperature	$\mathrm{T_{ch}}$	150	$^{\circ}\mathrm{C}$
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~150	°C

# 1.5 ± 0.1 1.5 ± 0.1 GATE SOURCE DRAIN **JEDEC**

SC-62

2-5K1D

**EIAJ** 

**TOSHIBA** 

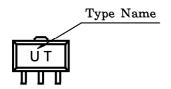
4.6MAX

Unit in mm

0<u>.4</u> ± 0.05

1.6MAX

#### **MARKING**



#### ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Output Power	PO	$ m V_{DS}\!=\!6V,\ f\!=\!849MHz$ $ m Pi\!=\!23dBmW$	31	_	_	dBmW
Drain Efficiency	$\eta_{\mathbf{D}}$	$V_{ m DS}$ =6V, f=849MHz Pi=23dBmW, PO=31dBmW	55	_	_	%
Drain-Source Breakdown Voltage	V (BR) DSS	$V_{GS}=0$ , $I_D=1\mu A$	10	_	_	V
Drain Cut-off Current	$I_{ m DSS}$	$V_{DS}=6V, V_{GS}=0$	_	_	100	nA
Threshold Voltage	$ m V_{th}$	$V_{DS} = 6V, I_{D} = 500 \mu A$	1.0	1.4	1.8	V
Gate-Source Leakage Current	$I_{GSS}$	$V_{GS}=6V, V_{DS}=0$	_	_	±100	nA

#### **CAUTION**

This transistor is the electrostatic sensitive device.

Please handle with caution.

961001EAA1

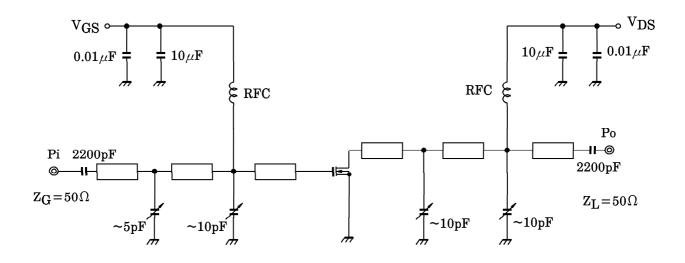
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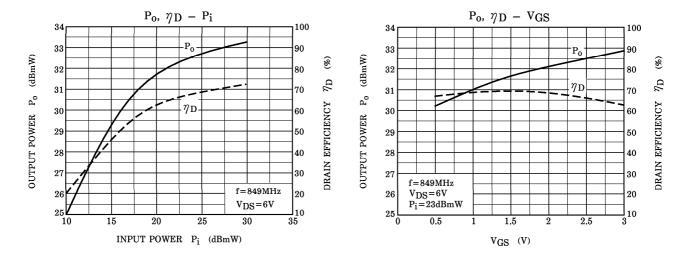
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#### RF OUTPUT POWER TEST FIXTURE





#### **CAUTION**

These are only typical curves and devices are not necessarily guaranteed at these curves.